

PCN Number:	20170228002-005		PCN Date:	April 18, 2017					
Title:	Qualification of a new Die Attach Material for Select Devices								
Customer Contact:	PCN Manager	Dept:	Quality Services						
Proposed 1st Ship Date:	Oct 11, 2017	Estimated Sample Availability:	Date provided at sample request						
Change Type:									
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Site				
<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Material				
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Bump Process				
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Site				
<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Materials				
				<input type="checkbox"/>	Wafer Fab Process				
PCN Details									
Description of Change:									
This notification is to announce the qualification of a new die attach material for the devices in the product affected section below as follows:									
<table border="1"> <thead> <tr> <th>Current</th> <th>Proposed</th> </tr> </thead> <tbody> <tr> <td>8087417</td> <td>4222215</td> </tr> </tbody> </table>						Current	Proposed	8087417	4222215
Current	Proposed								
8087417	4222215								
Reason for Change:									
Die Attach Supplier change no longer producing current material. No current material available after PCN expiration.									
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):									
None									
Anticipated impact on Material Declaration									
<input type="checkbox"/>	No Impact to the Material Declaration	<input checked="" type="checkbox"/>	Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the TI ECO website .						
Changes to product identification resulting from this PCN:									
None									
Product Affected:									
TPS5450MDDAREP	TPS73601MDCQREP	V62/06626-01YE	V62/90644-01XE						

Qualification Report

Qualification of 4222215 Die Attach Epoxy as Replacement of End of Life 8087417 Epoxy for Commercial Devices

Product Attributes

Attributes	Qual Device: OPA2211AIDDAR	Qual Device: OPA454AIDDAR	Qual Device: REG1117A/2K5	Qual Device: TPS7xxxQDCQR
Assembly Site	HNT	HNT	HNT	HNT
Package Family	SOIC (SO PowerPAD)	HSOIC (PowerPAD)	SOT223	SOT223
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	FR-BIP-1	DL LIN	SH-BIP-1	TSMC-WF2
Wafer Process	BICOM3-HV	LBC-SOI	BIPOLAR	0.60UM-TSMC

- QBS: Qual By Similarity
- Qual Device REG1117A/2K5 is qualified at LEVEL1-260C
- Qual Device OPA2211AIDDAR is qualified at LEVEL1-260C
- Qual Device OPA454AIDDAR is qualified at LEVEL2-260C
- Qual Device TPS7xxxQDCQR is qualified at LEVEL2-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: OPA2211AIDDAR	Qual Device: OPA454AIDDAR	Qual Device: REG1117A/2K5	Qual Device: TPS72xxxQDCQR
PC	Automotive Preconditioning	Level 2-260C	-	-	-	3/308/0
PC	Preconditioning	Level 1-260C	3/154/0	-	3/231/0	-
PC	Preconditioning	Level 2-260C	-	3/308/0	-	-
AC	Autoclave, 121C	96 Hours	3/77/0	3/77/0	3/77/0	3/77/0
DS	Die Shear	QSS 009-009	3/10/0	3/10/0	3/10/0	3/10/0
ED	Electrical Distributions	Cpk>1.67	-	-	-	3/30/0
ED	Electrical Characterization	-	3/15/0	3/15/0	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	3/77/0
HTOL	Life Test, 125C	1000 Hours	-	-	-	3/77/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	3/77/0	3/77/0	3/77/0
MQ	Manufacturability	(per mfg. Site specification)	3/0/0	3/0/0	3/0/0	-
MQ	Manufacturability (Auto Assembly)	(per automotive requirements)	-	-	-	3/0/0
MSL	Moisture Sensitivity	Level 1-260C	-	-	3/12/0	-
MSL	Thermal Integrity Sequence	Level 1-260C	3/12/0	-	-	-
MSL	Thermal Integrity Sequence	Level 2-260C	-	3/12/0	-	3/12/0
TC	Temperature Cycle, -65C/150C	500 Cycles	3/77/0	3/77/0	3/77/0	3/77/0
TC-WBP	Post Temp Cycle Bond Pull	30 ball bonds, min. 5 units	-	-	-	3/5/0
TS	Thermal Shock, -65C/+150C	500 Cycles	-	3/77/0	-	-
XRAY	X-ray	(top side only)	3/5/0	3/5/0	3/5/0	3/5/0
YLD	FTY and Bin Summary	-	3/0/0	3/0/0	3/0/0	3/0/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable.

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours and 170C/420 Hours.

- The following are equivalent Temperature Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles.

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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